

GRASS 2024 – Straylight Mitigation
Trento, October 1st, 2024

Theoretical modeling and experimental characterization of the light fields retro-reflected and/or backscattered by optical components

Michel LEQUIME, Alexandra CARREZ, Adrien BOLLIAND, Claude AMRA, and Myriam ZERRAD

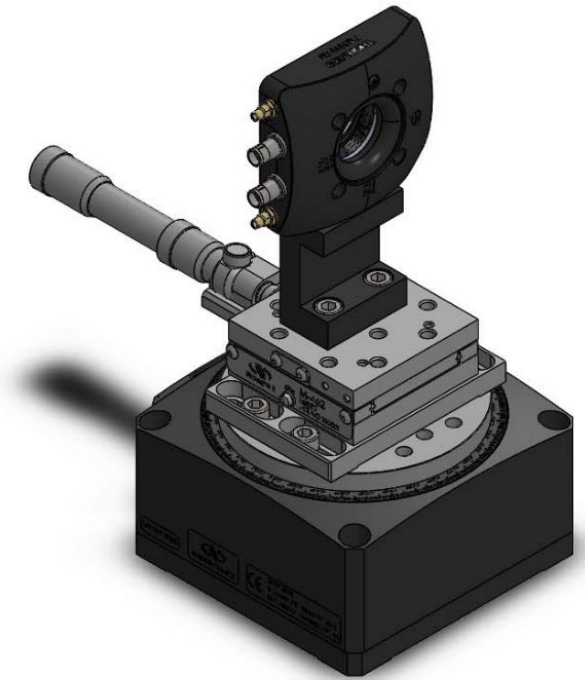
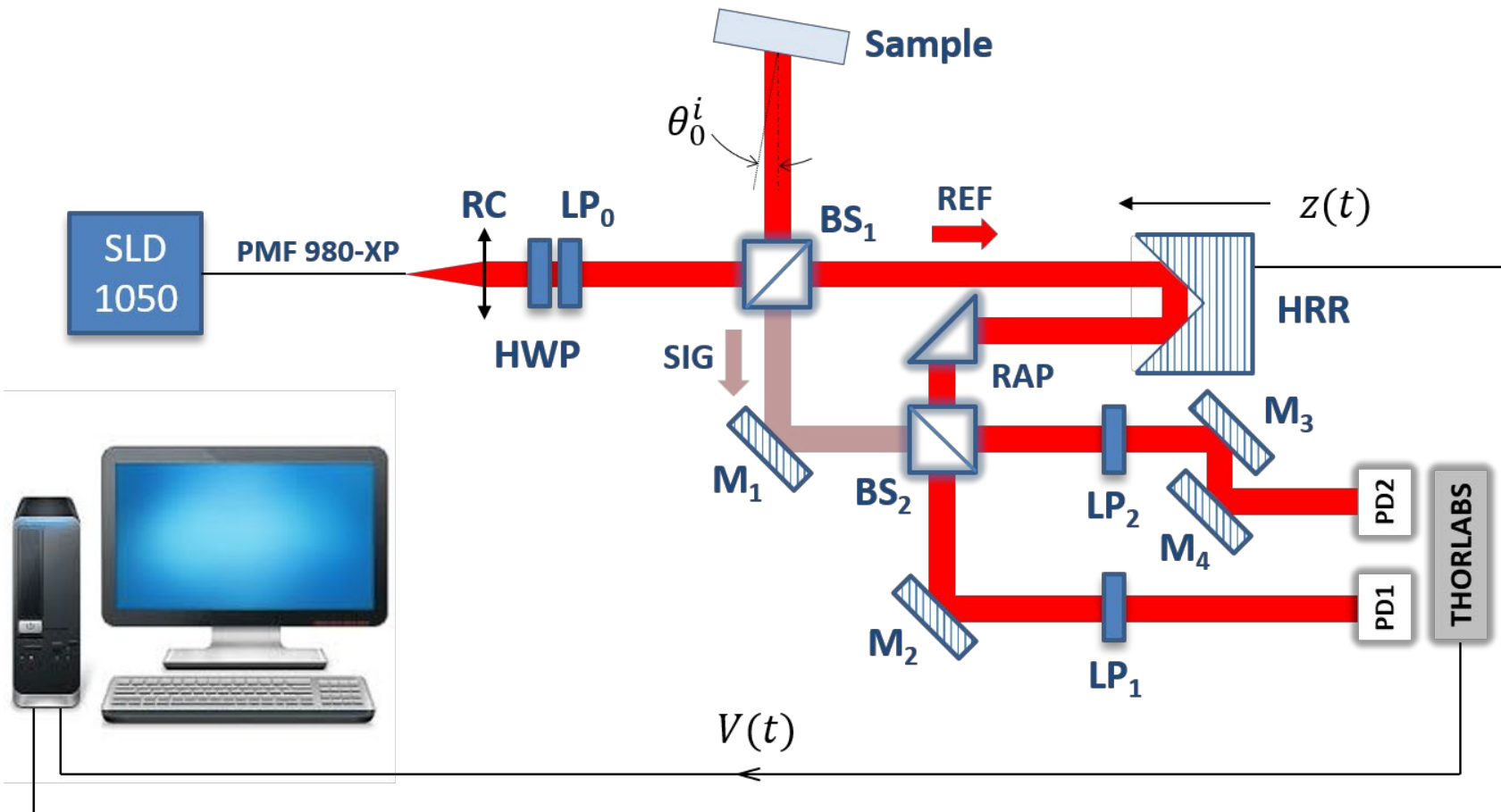
Introduction

- **Light scattering perturbation is a coherent effect in gravitational wave interferometric detectors**
 - *Amplitude and phase of the scattered field*
- **Only the part that can be coherently mixed with the main beam is relevant**
 - *State of polarization of the scattered field*
- **Surface roughness and point defects are the main sources of light scattering**
 - *Fast angular variations of the scattered field (speckle grains, Airy patterns)*

Introduction

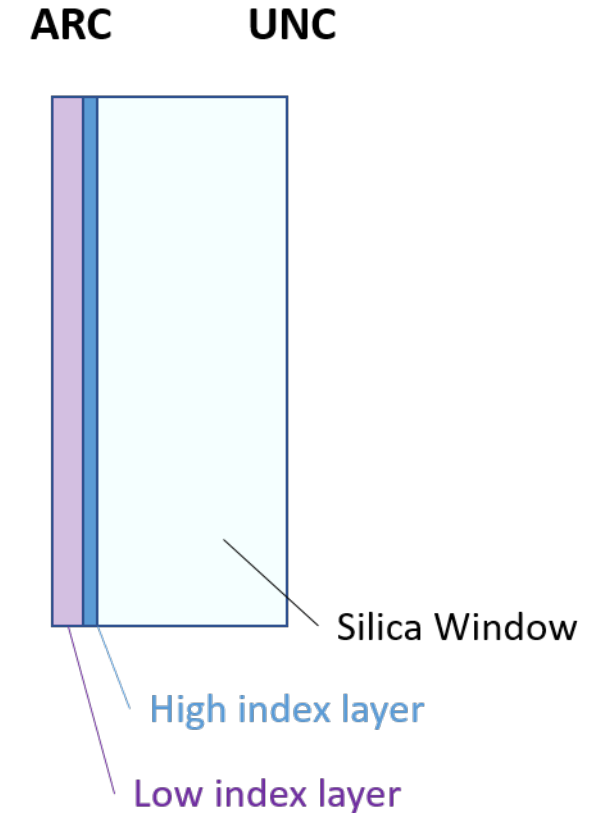
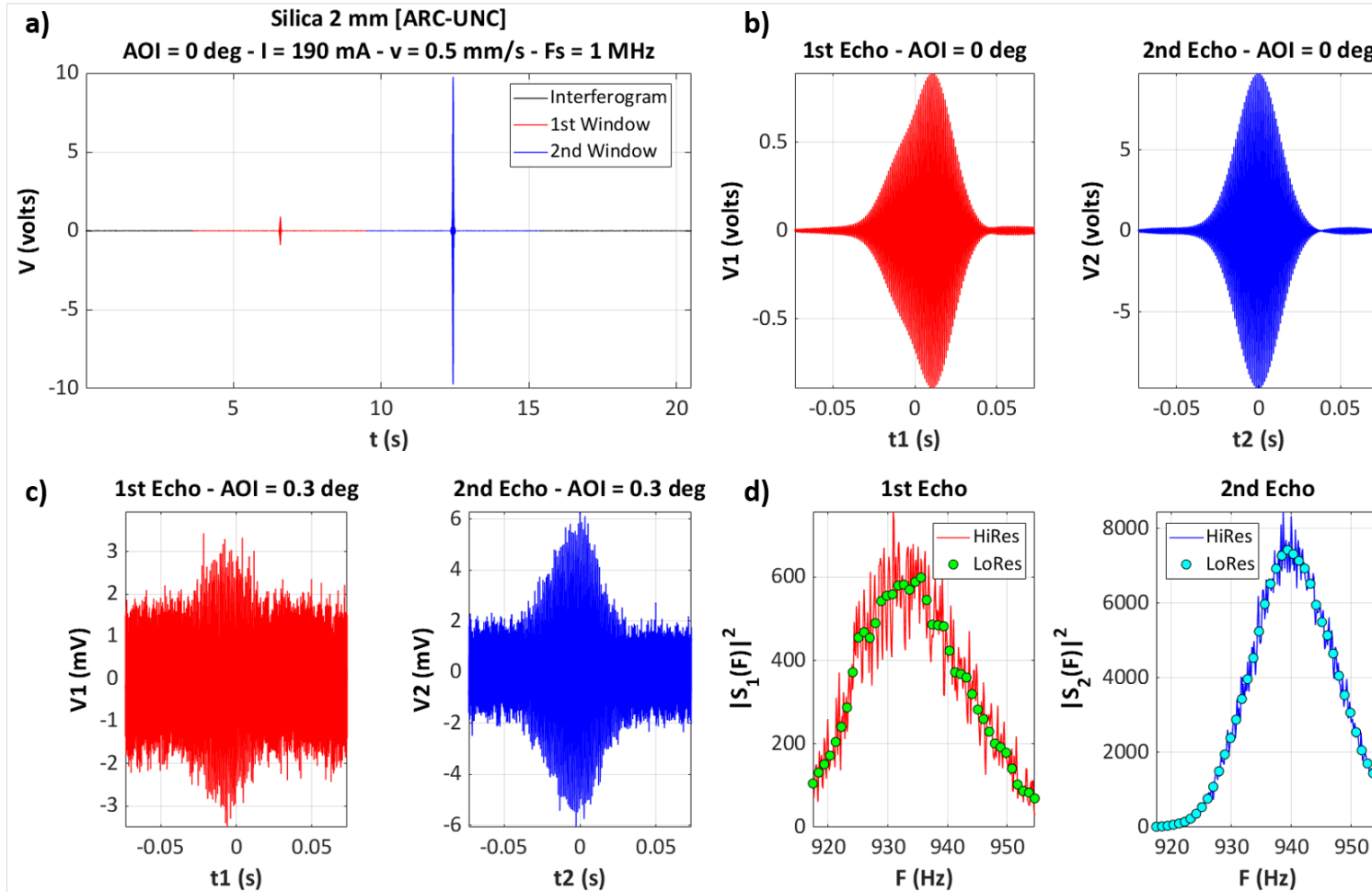
- **f_{SC} approaches are mainly based on incoherent measurements**
 - *Angle Resolved Scattering (SALSA, CASIX)*
- **Development of coherent tools**
 - *LAPP – Homodyne detection in monochromatic lightning (component mounted on an oscillating breadboard)*
 - *ARTEMIS – FMCW scheme with ranging capability (characterization of a set of components in a fixed configuration)*
 - *Institut FRESNEL – BARRITON (low-coherence interferometry with ranging capability and spectrally resolved amplitude/phase measurement)*
 - ✓ *Measurement of the wavelength dependence of the retroreflection of high efficiency AR coatings*
 - ✓ *Recording of speckle and Airy patterns in a backscatter configuration*

BARRITON



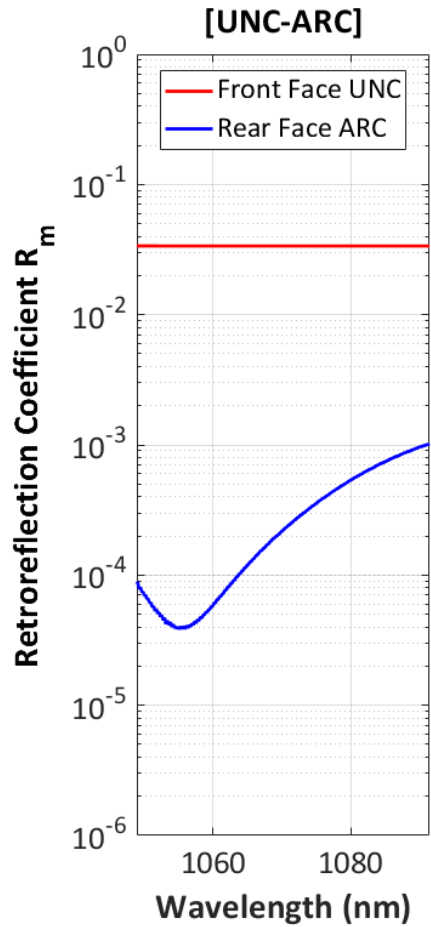
Angular resolution: 0.1 mdeg

BARRITON

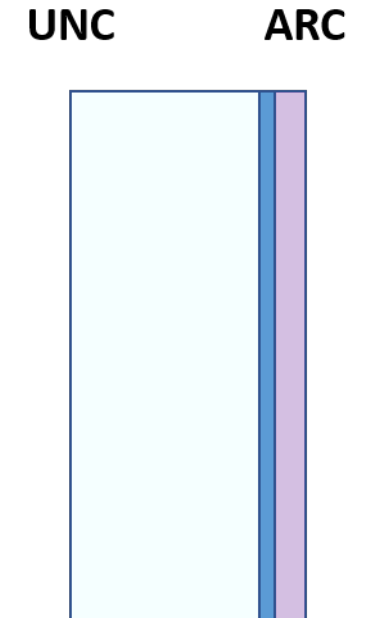


$$\lambda = \frac{2v}{F}$$

Experimental characterization

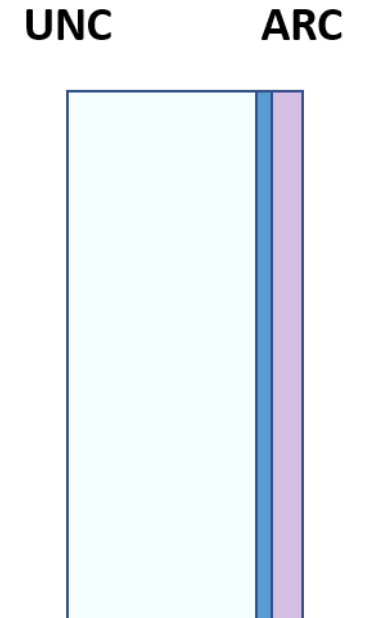
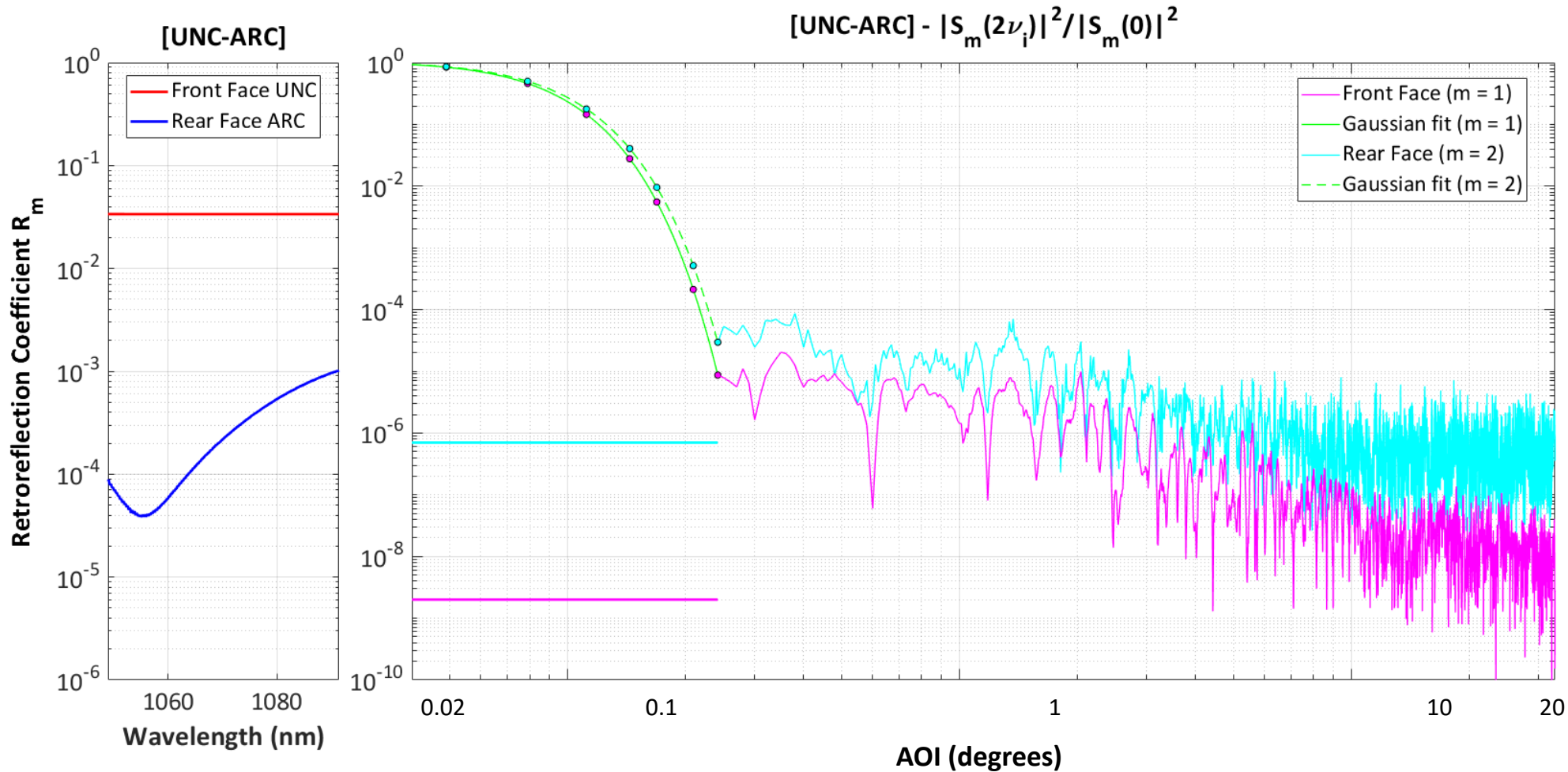


$$ARS_m(\lambda, \nu) = \frac{\pi W_S^2}{\lambda^2} R_m(\lambda) \frac{|S_m(\nu)|^2}{|S_m(0)|^2}$$

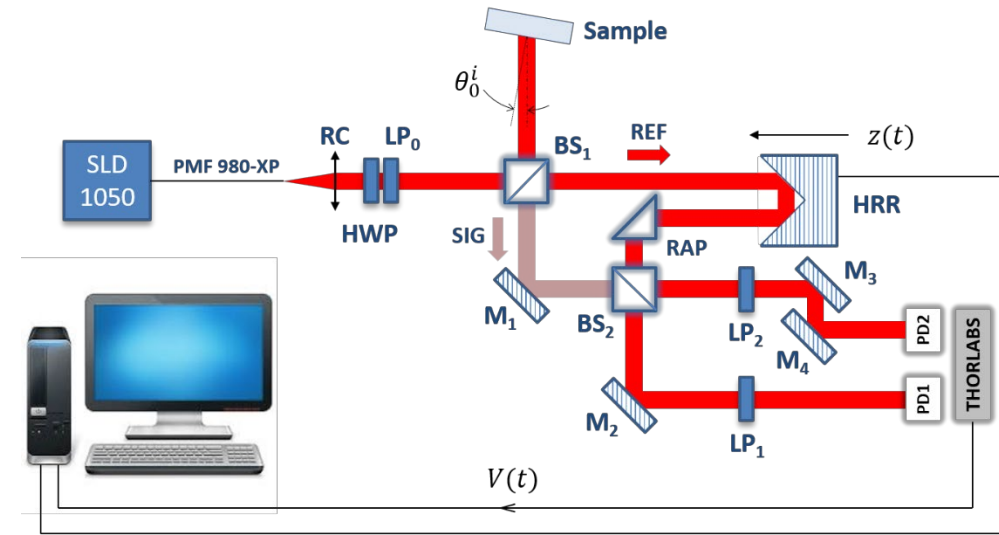


Experimental characterization

Polarization TE
Noise floor $\sim 10^{-11}$



Theoretical modeling



- **Lighting beam**

- Gaussian beam with a waist located in the image focal plane of RC ($w_f = 0.7$ mm)

- **Interferometer**

- Free space propagation of the reference beam to the photodiodes (Fresnel approximation)

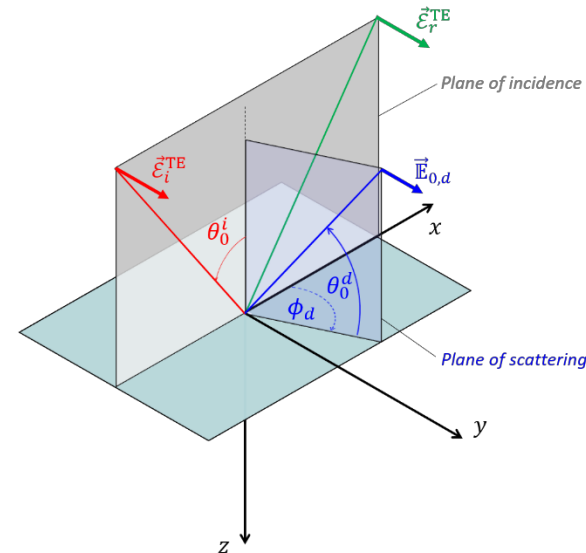
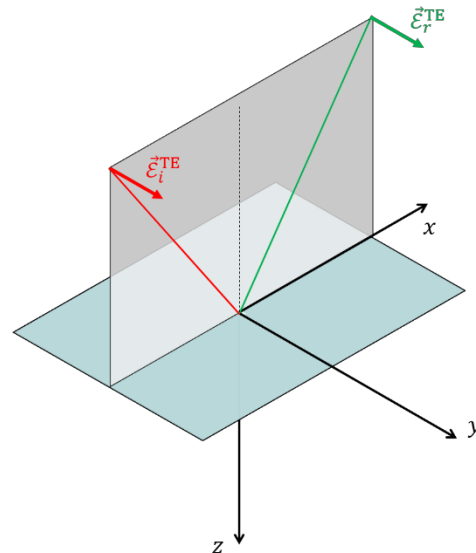
$$\vec{E}_{ref,1}(x, y, z; f) = t_1 t_2 \frac{e^{ikz}}{1 + iz/z_R} e^{-\frac{x^2 + y^2}{w_f^2(1 + iz/z_R)}} \vec{E}_i$$

- Free space propagation of the signal beam to the sample
- Reflection/Scattering of the signal beam at the sample surface (AOI θ_0^i)
- Free space propagation of the reflected/backscattered fields from the sample to the photodiodes

Theoretical modeling

■ At the sample surface

- Decomposition of the incident field spatial repartition into elementary plane waves
- Calculation of the plane waves reflected and scattered from the sample surface



- Coherent mixing with the reference beam

Theoretical modeling

- **Scattered field**

$$\propto \hat{h}_S^i(\vec{v}_d) \quad \vec{v}_d = \begin{bmatrix} (n_0/\lambda) \sin \theta_0^d \cos \phi_d \\ (n_0/\lambda) \sin \theta_0^d \sin \phi_d \end{bmatrix} \quad \vec{v}_i = \begin{bmatrix} (n_0/\lambda) \sin \theta_0^i \\ 0 \end{bmatrix}$$

$$h_S^i(x, y) = h(x, y) S_i(x, y)$$

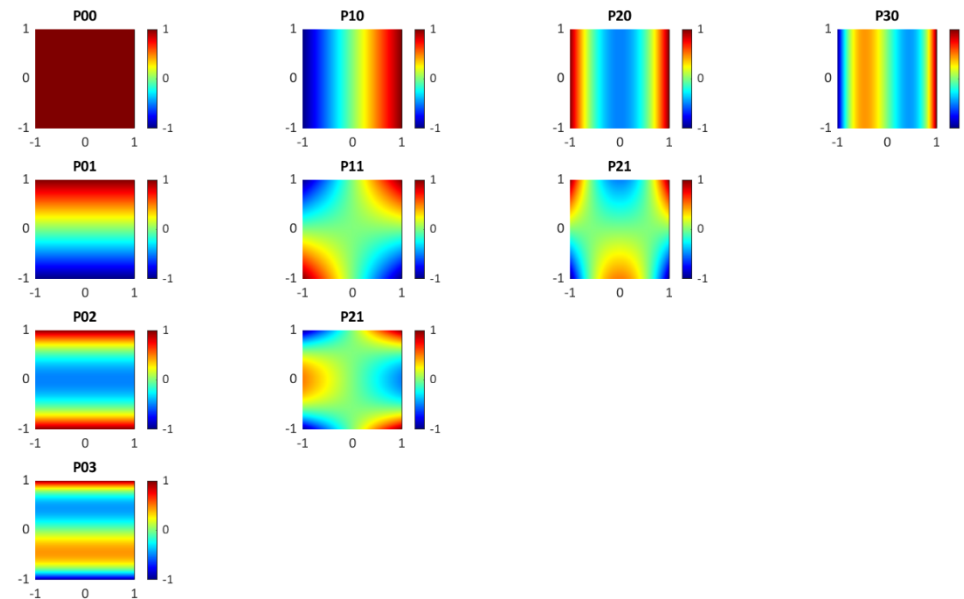
$$S_i(x, y) = \frac{1}{1 + i d/z_R} e^{-\frac{(x \cos \theta_0^i)^2 + y^2}{w_f^2(1 + i d/z_R)}} e^{i k_0(d + x \sin \theta_0^i)}$$

- **Backscattered field** $\theta_0^d = \theta_0^i ; \phi_d = \pi \implies \propto \hat{h}_S^i(-v_i, 0)$

Theoretical modeling

■ Method

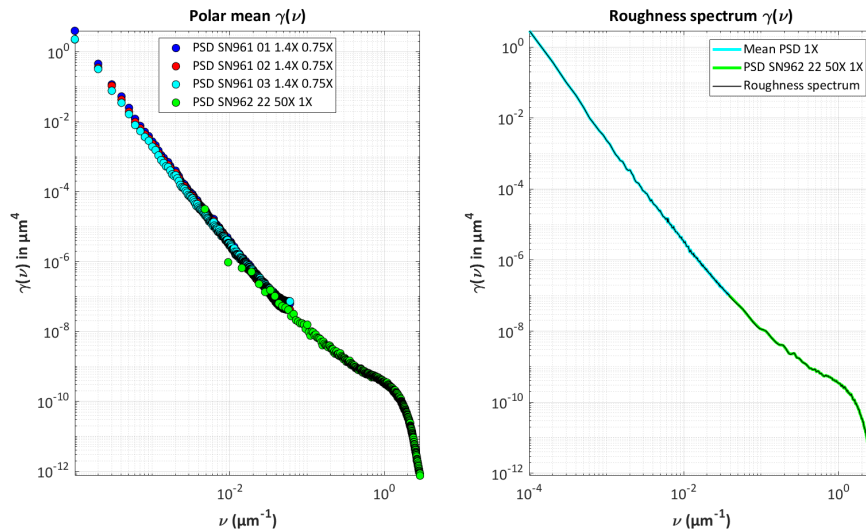
- *To define a realistic representation of a surface with both waviness and roughness*
 - ✓ *Either directly derived or numerically generated from experimental results*
 - ✓ *Waviness : generated on the basis of 2D Legendre polynomials*



Theoretical modeling

■ Method

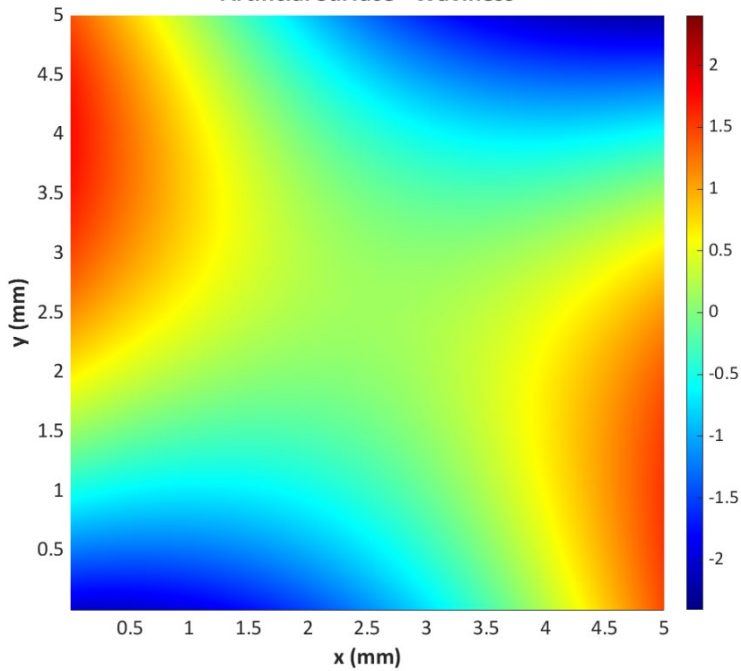
- **To define a realistic representation of a surface with both waviness and roughness**
 - ✓ Either directly derived or numerically generated from experimental results
 - ✓ **Waviness** : generated on the basis of 2D Legendre polynomials
 - ✓ **Roughness** : generated from polar averaging of an experimental PSD



$$h(x, y) = FT^{-1}[\sqrt{S\bar{\gamma}(\nu)} e^{i\phi(\nu_x, \nu_y)}] \quad \text{where } \nu = \sqrt{\nu_x^2 + \nu_y^2}$$

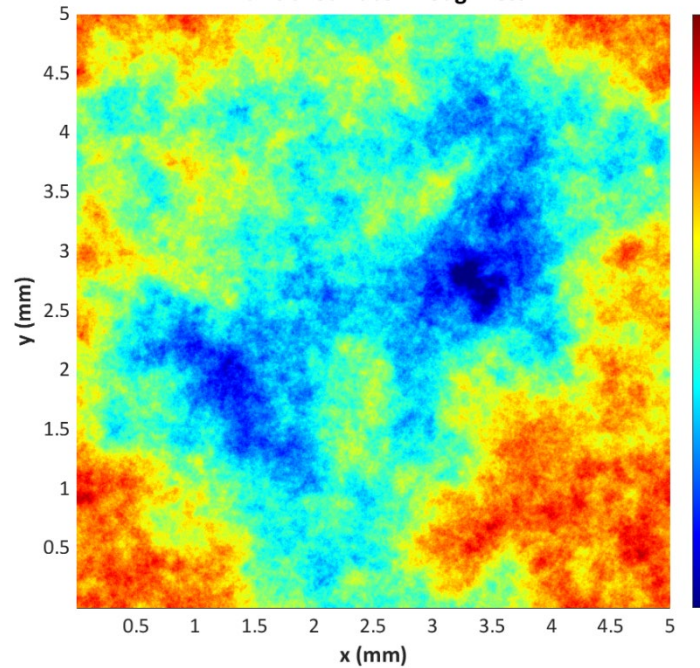
High quality surface

Artificial Surface - Waviness



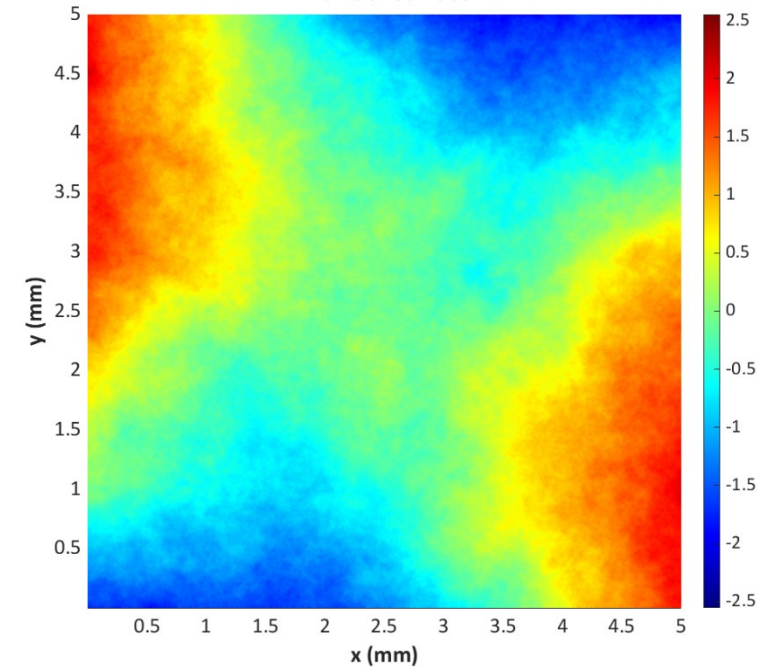
$$\sigma_w = 2.1 \text{ nm}$$

Artificial Surface - Roughness

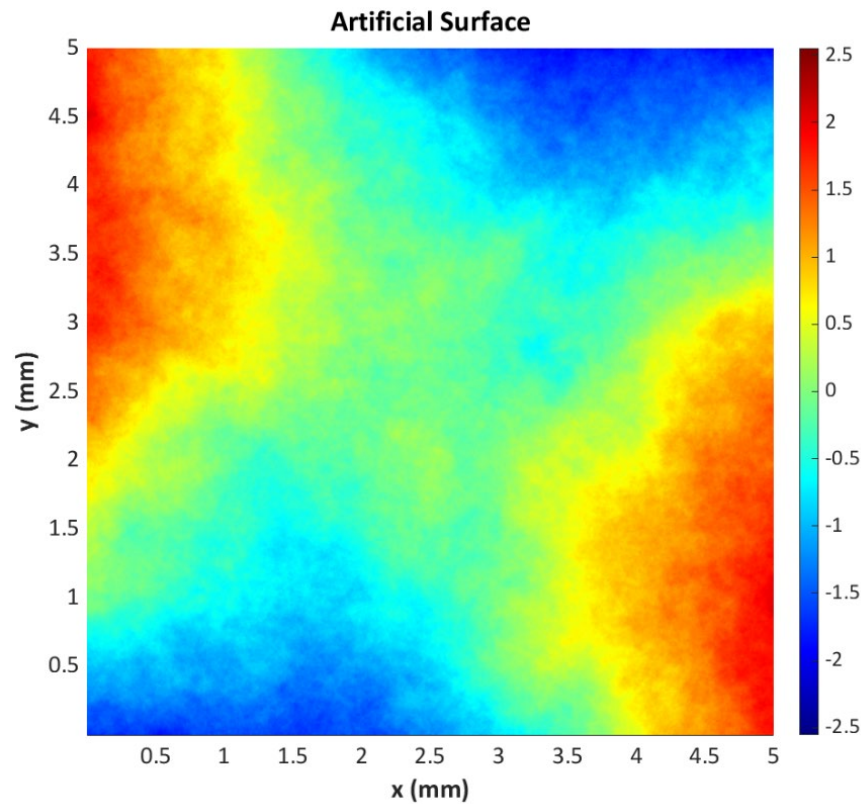


$$\sigma_r = 0.3 \text{ nm}$$

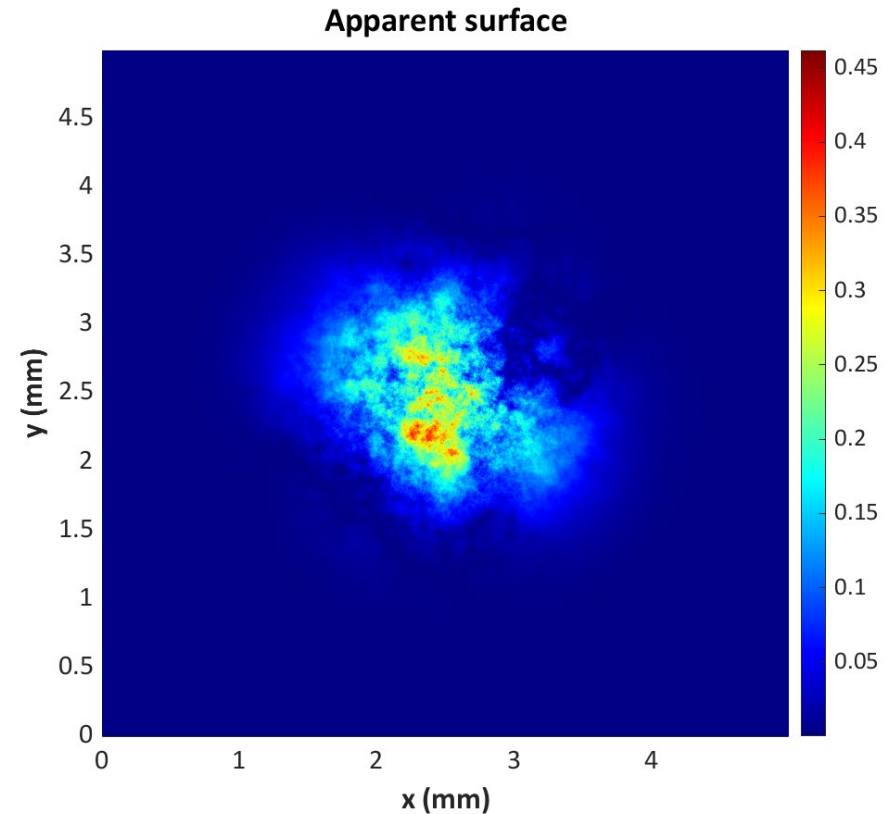
Artificial Surface



High quality surface

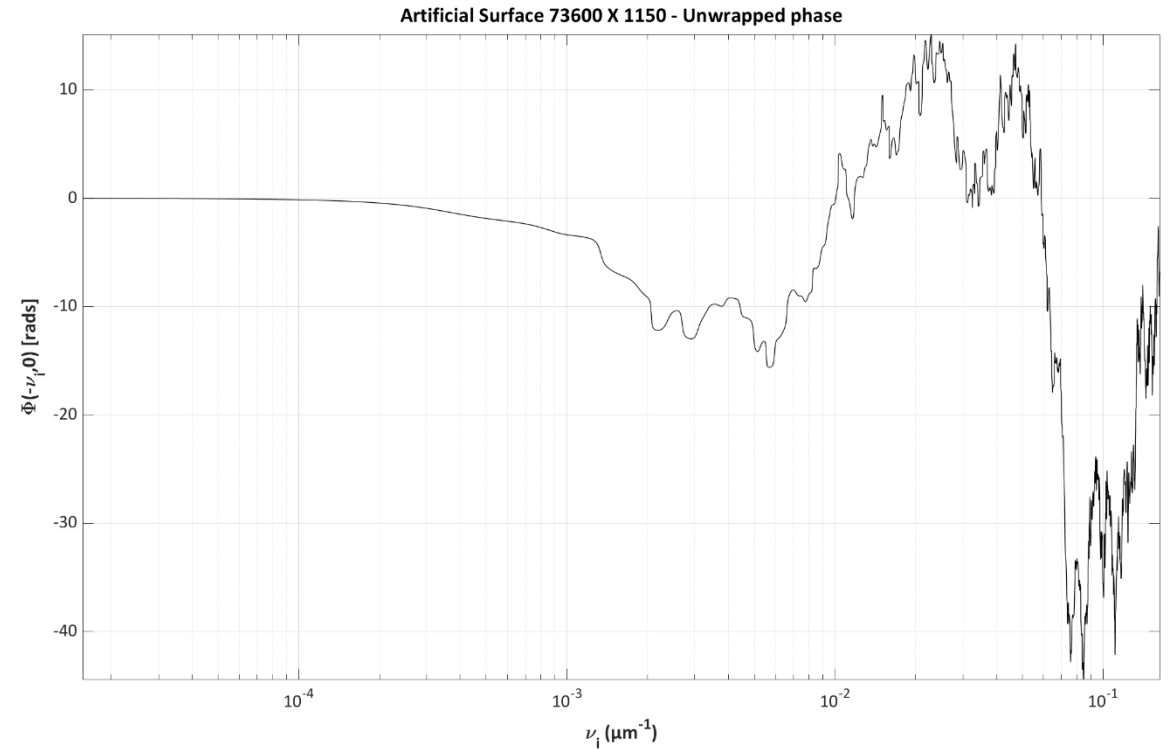
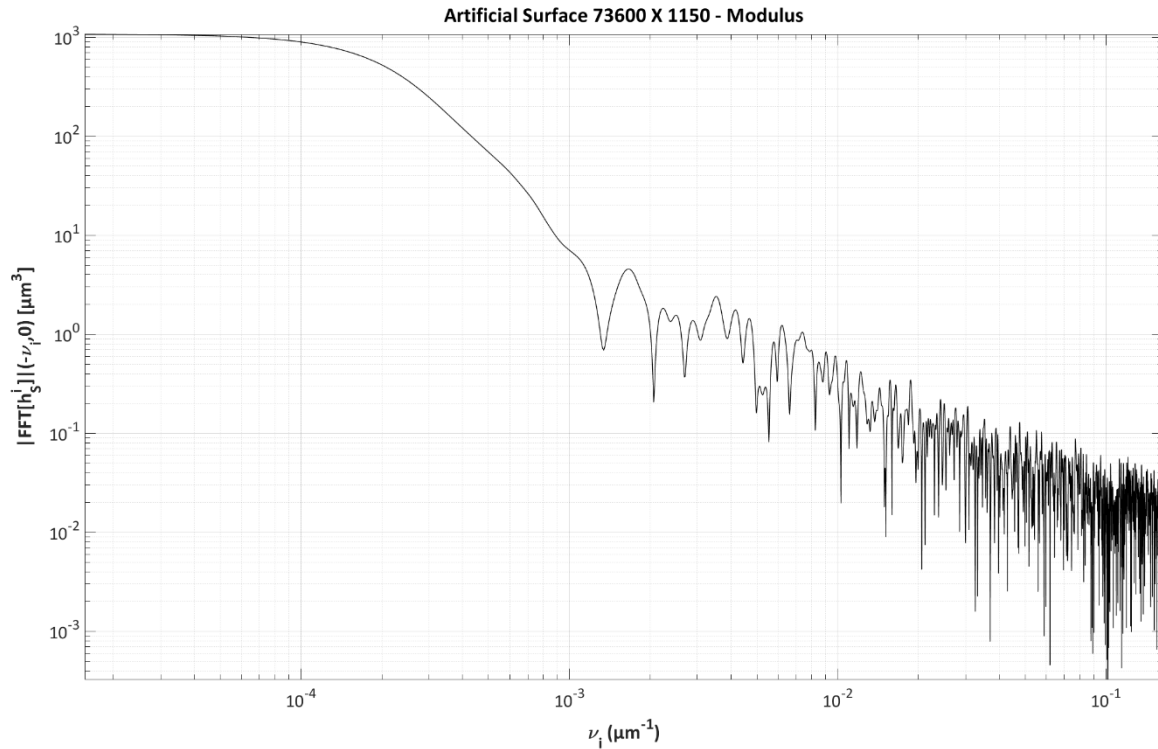


$$h(x, y)$$

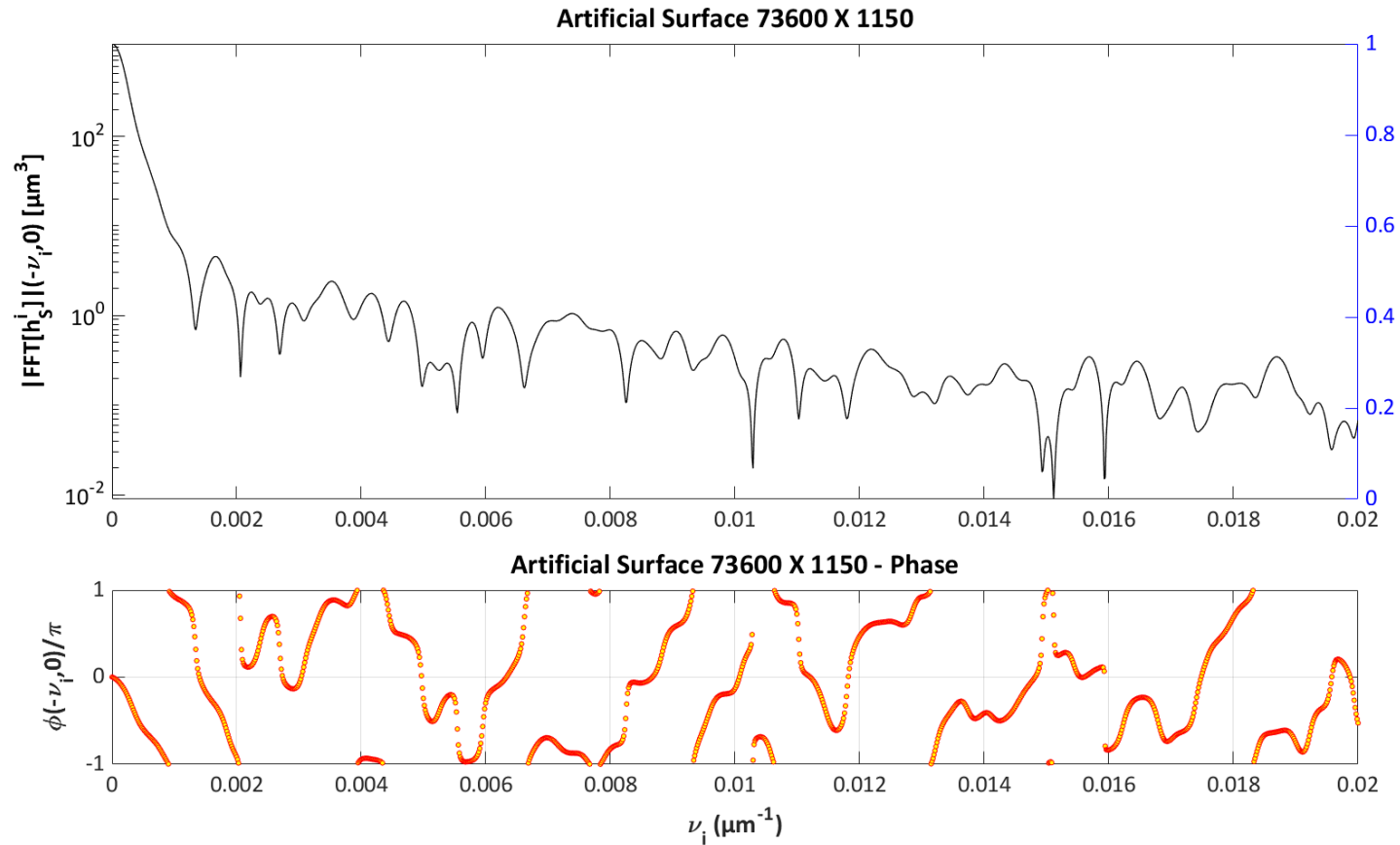


$$h_S^i(x, y) = h(x, y)S_i(x, y)$$

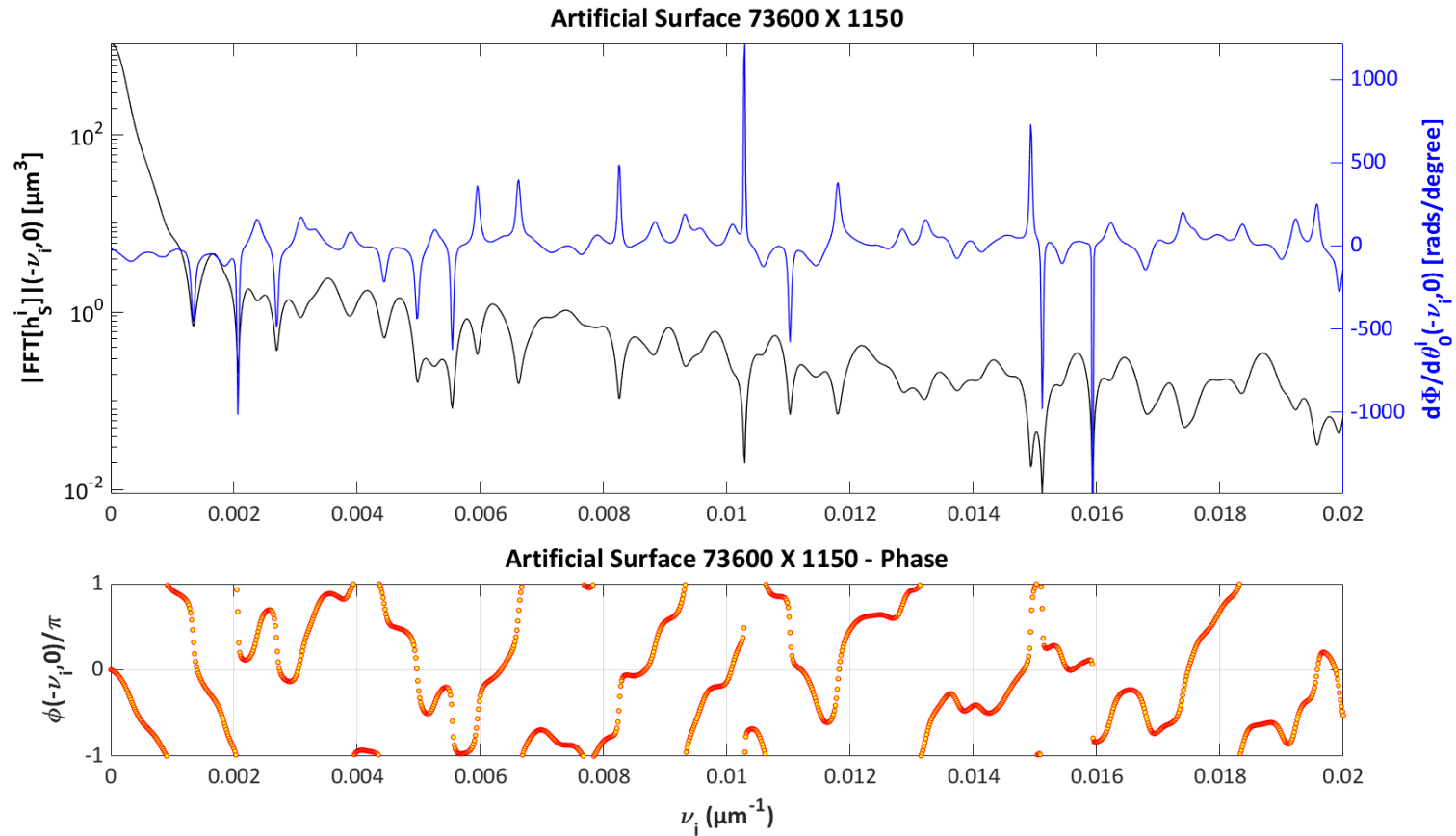
High quality surface



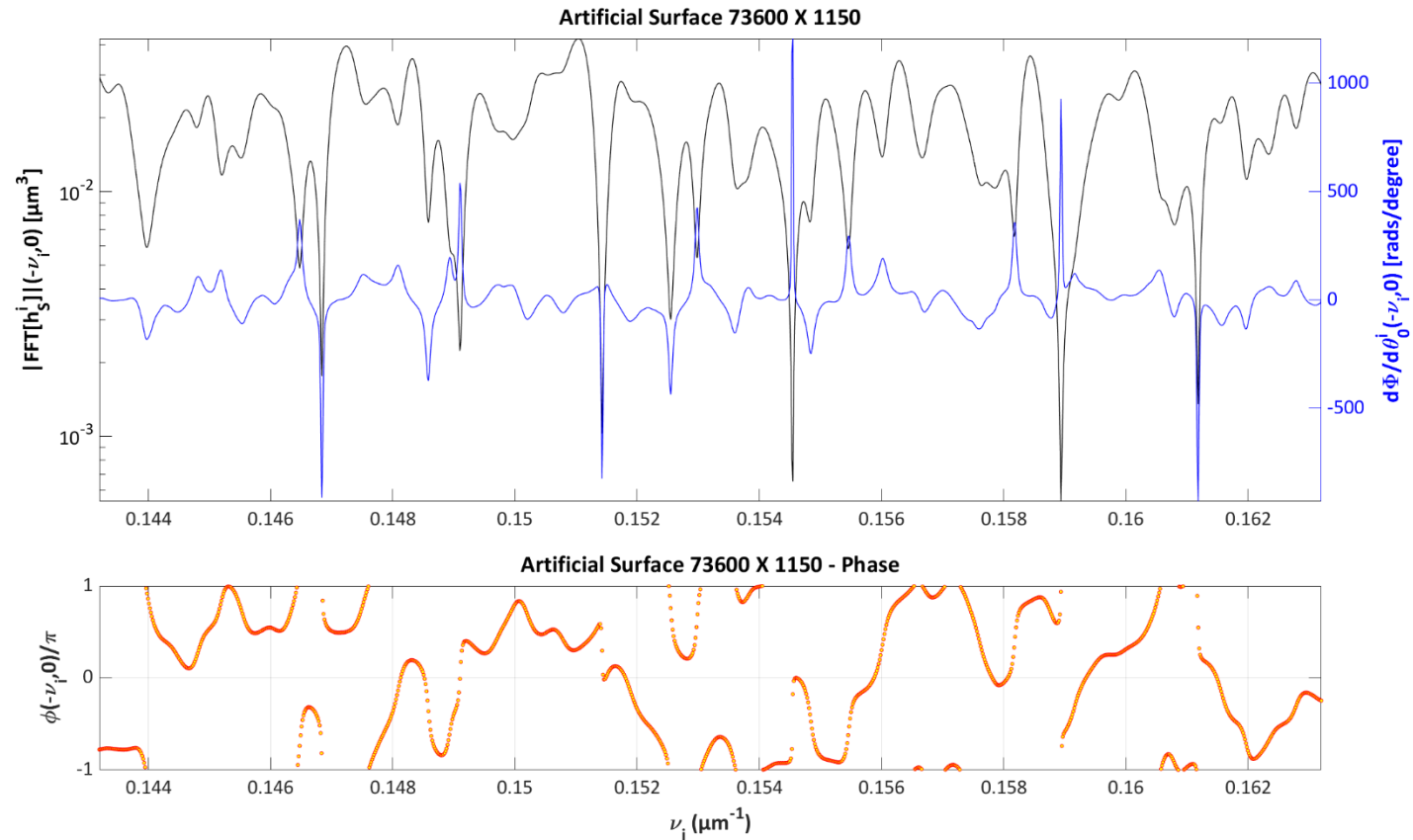
High quality surface



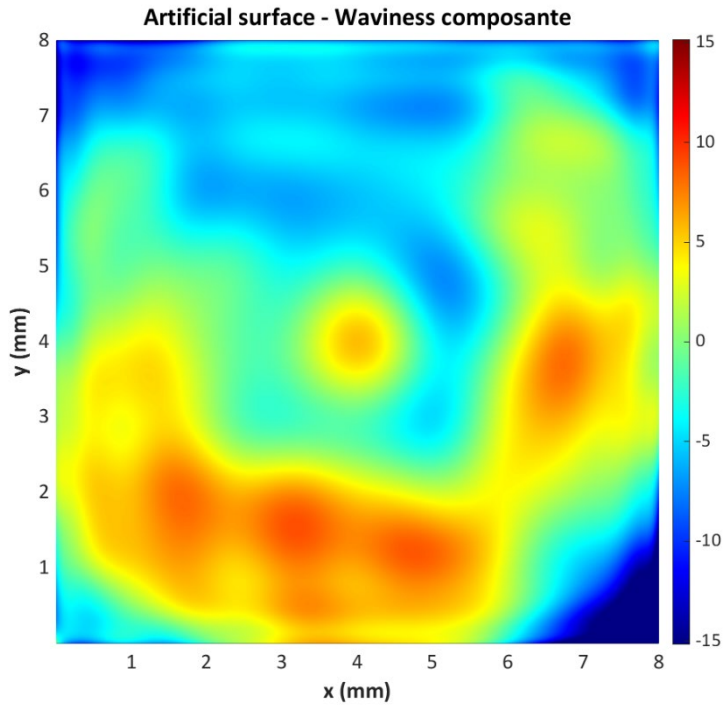
High quality surface



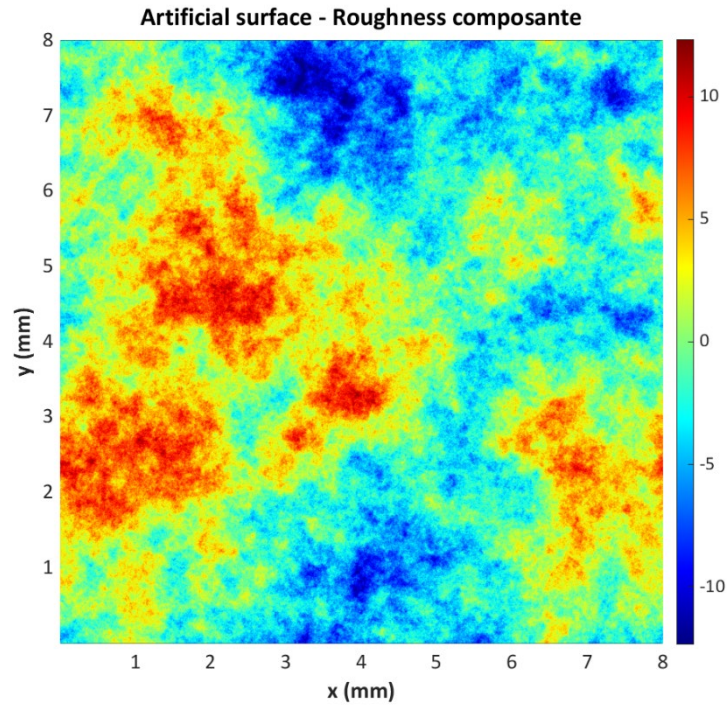
High quality surface



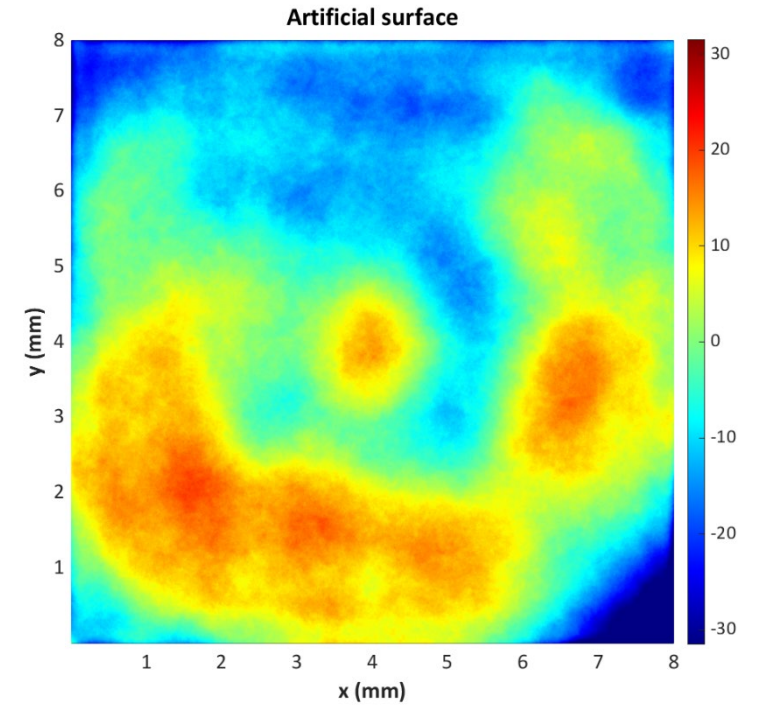
Low quality surface



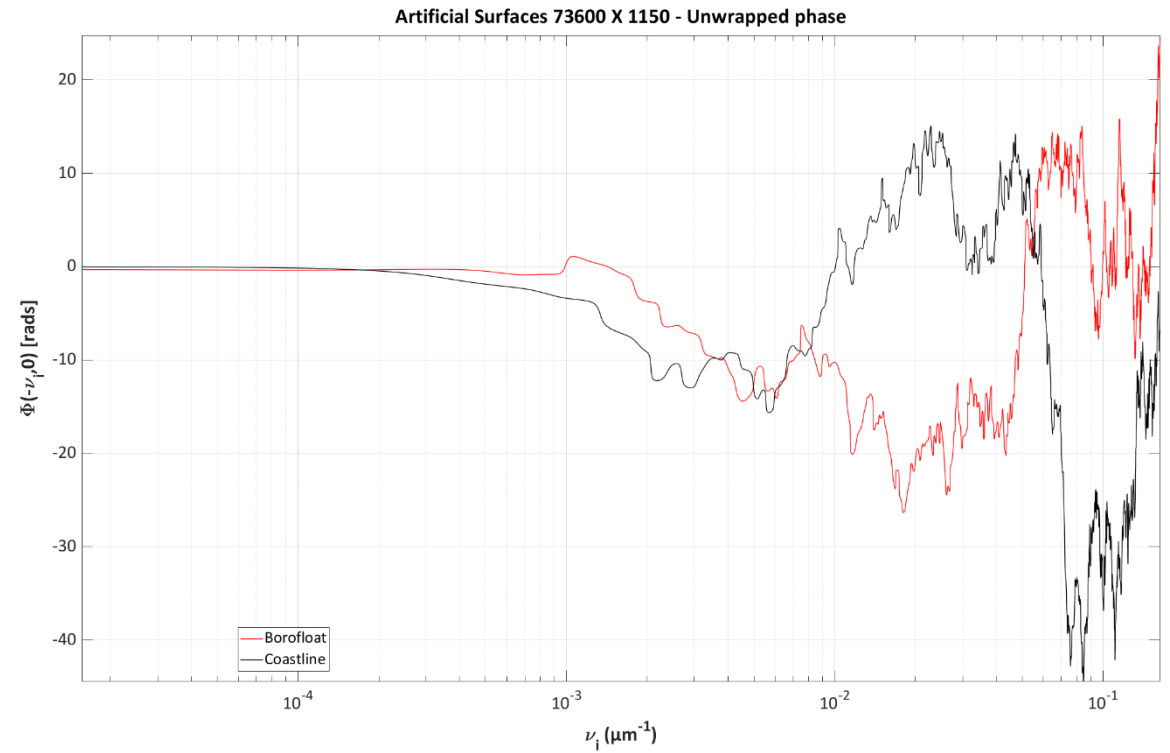
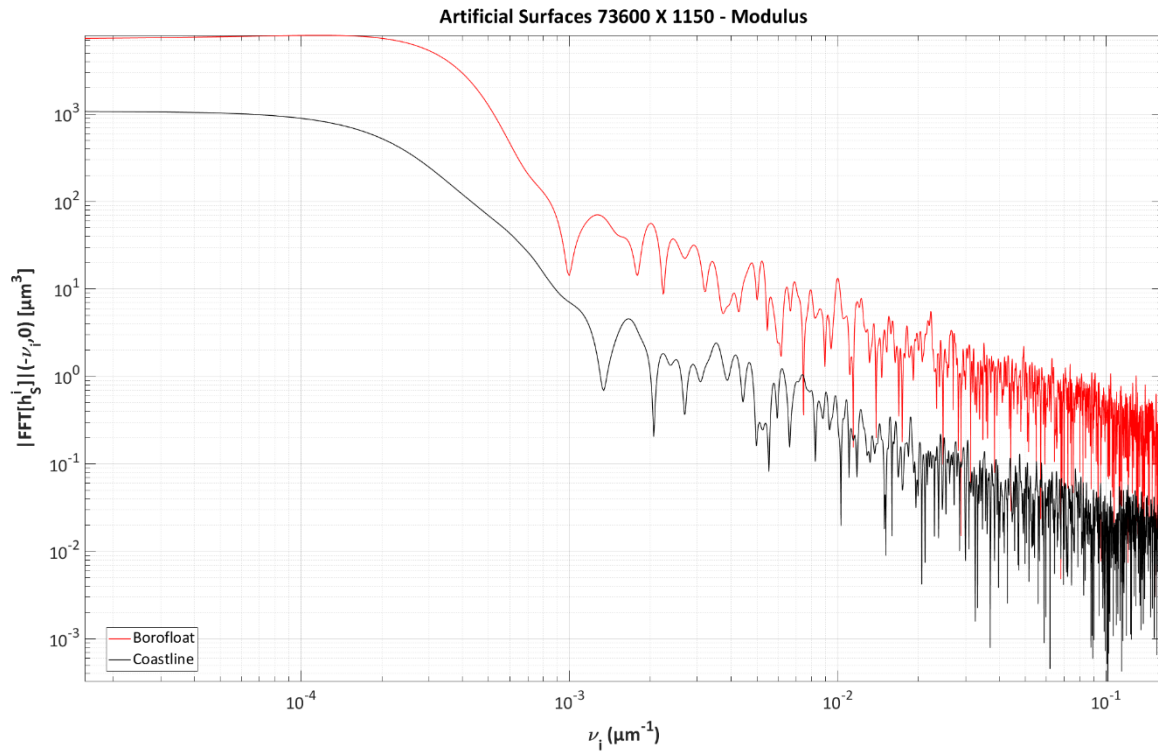
$$\sigma_w = 10.1 \text{ nm}$$



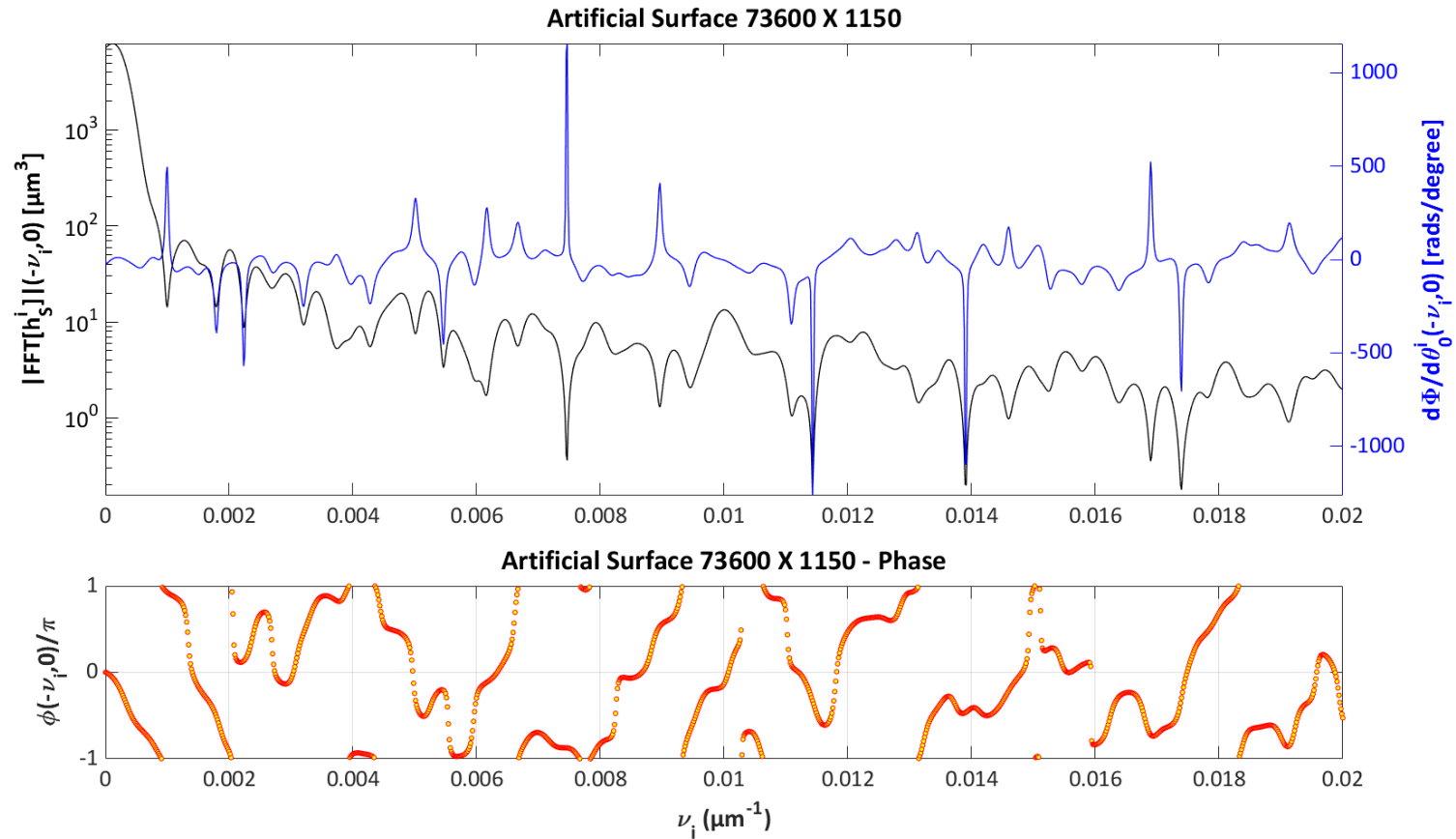
$$\sigma_r = 2.1 \text{ nm}$$



Low quality surface



Low quality surface



Conclusion

■ Main achievements

- *Generation of artificial surfaces with realistic waviness and roughness features*
- *Good agreement between experimental results and theoretical modelling of coherent backscattering from a surface*
- *Very fast dependence of the phase of the scattered field with respect to small change in the angular position of the surface*
 - ✓ *To be considered in the perturbation budget induced by light scattering*

■ Further activities

- *Integration and qualification of BARRITON 2 (expected noise floor $\sim 3 \times 10^{-14}$)*
- *Phase measurement of the field backscattered by a surface*



Thanks a lot for your kind attention!